

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re U.S. Patent Application  
Dimitri LEDERER et al.

Examiner: Unassigned

Group Art Unit: Unassigned

International Serial Number: PCT/BE2004/000137

International Filing Date: September 27, 2004

Atty. Docket: LEDE3001/JEK

For: METHOD OF MANUFACTURING A MULTILAYER SEMICONDUCTOR  
STRUCTURE WITH REDUCED OHMIC LOSSES

**PRELIMINARY AMENDMENT BEFORE EXAMINATION**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INTRODUCTORY COMMENTS**

Prior to examination of the above-identified application that accompanies this paper, please amend the application as shown below.

**AMENDMENTS**

**ABSTRACT:**

An abstract is added below under the heading "ABSTRACT OF THE DISCLOSURE".

**AMENDMENTS TO THE CLAIMS**

The amendments to the claims appear in the following pages under the heading "LIST OF CURRENT CLAIMS". The claim listing replaces all previous versions of the claims presented in this application, and indicates any currently presented amendments and the status of each of the listed claims.

The amendments to the claims of this application, which originated in a foreign country, are submitted before examination on the merits and are not intended to have a narrowing effect for the purpose of patentability, but rather are made for one or more of the following reasons: (i) to remove drawing reference numerals